WHAT IS CLAIMED IS:

- 1. A glass substrate of which the outer periphery portion is unprocessed.
- A glass substrate of which the outer periphery portion is unprocessed having the center of gravity as the center of rotation.
- 3. The glass substrate of which the outer periphery portion is unprocessed according to Claim 1, wherein the outer periphery edge surface is a free-form surface having a surface coarseness 2.5 nm, or less, and having a maximum surface coarseness of 150 nm, or less.
- 4. The glass substrate of which the outer periphery portion is unprocessed according to Claim 1, wherein E/ρ (E is the Young's modulus (GPa) and ρ is the specific gravity (g/cm³)) is 27 to 52.
- 5. The glass substrate of which the outer periphery portion is unprocessed according to Claim 1, wherein αs (αs is a linear thermal expansion coefficient in the range of 0°C to 100°C) is 40×10^{-7} /°C to 130×10^{-7} /°C.
- 6. A glass substrate of which the outer periphery portion is unprocessed, comprising amorphous glass material or crystallized glass material having the following composition: 65 wt.% to 85 wt.% of SiO_2 , 3 wt.% to 15 wt.% of Al_2O_3 , 0 wt.% to 12 wt.% of MgO, 0 wt.% to 10 wt.% of TiO_2 , 3 wt.% to 12 wt.% of Li_2O , 0 wt.% to 10 wt.% of ZnO, 0 wt.% to 5 wt.% of P_2O_5 and 0 wt.% to 10 wt.% of ZnO_2 .
 - 7. A glass substrate of which the outer periphery

portion is unprocessed, comprising amorphous glass material or crystallized glass material having the following composition: 45 wt.% to 60 wt.% of SiO_2 , 12 wt.% to 25 wt.% of Al_2O_3 , 12 wt.% to 25 wt.% of MgO, 0 wt.% to 12 wt.% of TiO_2 , 0 wt.% to 12 wt.% of Li_2O , 0 wt.% to 10 wt.% of ZnO, 0 wt.% to 5 wt.% of P_2O_5 , 0 wt.% to 10 wt.% of ZrO_2 , 0 wt.% to 5 wt.% of Nb_2O_5 , 0 wt.% to 5 wt.% of Ta_2O_5 and 0 wt.% to 5 wt.% of Y_2O_3 .

- 8. A glass substrate of which the outer periphery portion is unprocessed, comprising amorphous glass material having the following composition: 50 wt.% to 69 wt.% of SiO_2 , 0 wt.% to 15 wt.% of B_2O_3 , 4 wt.% to 25 wt.% of Al_2O_3 , 2 wt.% to 7 wt.% of Li_2O , 0 wt.% to 14 wt.% of Na_2O , 0 wt.% to 18 wt.% of K_2O , 0 wt.% to 6 wt.% of CaO, 0 wt.% to 3 wt.% of Ta_2O_5 , 0 wt.% to 6 wt.% of BaO, 0 wt.% to 6 wt.% of Sioint Microsimal Micr
- 9. A manufacturing method for a glass substrate of which the outer periphery portion is unprocessed, characterized in that a first lapping process, a second lapping process, a polishing process and a washing process are carried out after a press molding process is carried out so as to compress glass between an upper mold and a lower mold without regulating the edge surface of the outer periphery portion of the glass and, then, a crystallization process or an annealing process is carried out.
- 10. A manufacturing method for a glass substrate of which the outer periphery portion is unprocessed, characterized in that a center of gravity coring process

wherein a center hole is created using the center of gravity as the center of the hole is carried out and a first lapping process, a precision inner periphery edge surface process, an inner periphery edge surface polishing process, a second lapping process, a polishing process and a washing process are carried out after a press molding process is carried out so as to compress glass between an upper mold and a lower mold without regulating the edge surface of the outer periphery portion of the glass and, then, a crystallization process or an annealing process is carried out.